

U.S. Department of Commerce	Patent and Trademark Office	ocket No.	Serial No.
(PTO Form 1449 modified)		APPM/1931.P1	10/052,681
<b>SUPPLEMENTAL LIST OF PATENTS AND PUBLICATIONS CITED BY APPLICANT</b>		Applicant	Confirmation No.:
		Xi, et al.	TECHNOLOGY 4083
(Use several sheets if necessary)		Filing Date	Group
	Examiner Unknown	01/17/2002	RECEIVED PTO-647 AUG 24 2002

## **U.S. Patent Documents**

Examiner G. Pealton

Date Considered 6/11/03

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.

Examiner Q. Perrotta

Date Considered 6/11/03

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Xi, et al.

**Confirmation No.:**

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**Examiner      Unknown**

## Filing Date

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## **OTHER ART**

*Examiner Initial		Including Author, Title, Date, Pertinent Pages, Etc.
<i>gp</i>	C1	K. Min et al., "Comparative Study of Tantalum and Tantalum Nitride as a Diffusion Barrier for CU Metallization" J. Vac. Sc. Technol. B 14(5), Sept/Oct 1996, p 1-7.
<i>gp</i>	C2 ✓	International Search Report for PCT/US01/26751, dated May 27, 2002.
<i>gp</i>	C3 ✓	International Search Report for PCT/US01/24880, dated May 17, 2002.
<i>gp</i>	C4 ✓	International Search Report for PCT/US98/09751, dated September 16, 1998.

## **Examiner**

g Peialta

### Date Considered

6/11/03

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